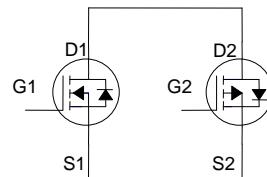


N & P-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

	N-CH	P-CH
BV <sub>DSS</sub>	30V	-30V
R <sub>DSON</sub> (MAX.)	21mΩ	40mΩ
I <sub>D</sub>	8A	-6A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNIT
Gate-Source Voltage		V <sub>GS</sub>	N-CH	P-CH	V
			±20	±20	
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	8	-6	A
	T <sub>C</sub> = 100 °C		6	-5	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	32	-24	
Avalanche Current		I <sub>AS</sub>	15	-15	
Avalanche Energy	L = 0.1mH, ID=10A, RG=25Ω (N) L = 0.1mH, ID=-10A, RG=25Ω (P)	E <sub>AS</sub>	5	5	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.05mH	E <sub>AR</sub>	2.5	2.5	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	21		W
	T <sub>C</sub> = 100 °C		8.3		
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150		°C

100% UIS testing in condition of V<sub>D</sub>=15V, L=0.1mH, V<sub>G</sub>=10V, I<sub>L</sub>=8A, Rated V<sub>DS</sub>=30V N-CH

100% UIS testing in condition of V<sub>D</sub>=15V, L=0.1mH, V<sub>G</sub>=-10V, I<sub>L</sub>=-6A, Rated V<sub>DS</sub>=-30V P-CH

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>		6	°C / W
Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>		42	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

<sup>3</sup>90°C / W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

**ELECTRICAL CHARACTERISTICS (T<sub>C</sub> = 25 °C, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT	
			MIN	TYP	MAX		
<b>STATIC</b>							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	N-CH	30		V	
		V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	P-CH	-30			
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	N-CH	1	1.5	3	
		V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	P-CH	-1	-1.5	-3	
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	N-CH			±100	
		V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	P-CH			±100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	N-CH			1	
		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V	P-CH			-1	
		V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C	N-CH			25	
		V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C	P-CH			-25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	N-CH	8		A	
		V <sub>DS</sub> = -5V, V <sub>GS</sub> = -10V	P-CH	-6			
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 8A	N-CH		17	21	
		V <sub>GS</sub> = -10V, I <sub>D</sub> = -6A	P-CH		35	40	
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 6A	N-CH		25	30	
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	P-CH		55	65	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 8A	N-CH		16	S	
		V <sub>DS</sub> = -5V, I <sub>D</sub> = -6A	P-CH		16		
<b>DYNAMIC</b>							
Input Capacitance	C <sub>iss</sub>	N-CH V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz P=CH V <sub>GS</sub> = 0V, V <sub>DS</sub> = -15V, f = 1MHz	N-CH		520		
			P-CH		820		
Output Capacitance	C <sub>oss</sub>		N-CH		88		
			P-CH		122		
Reverse Transfer Capacitance	C <sub>rss</sub>		N-CH		62		
			P-CH		97		

Total Gate Charge <sup>1,2</sup>	$Q_g(V_{GS}=10V)$ $Q_g(V_{GS}=-10V)$	N-CH $V_{DS} = 15V, V_{GS} = 10V,$ $I_D = 8A$ P-CH $V_{DS} = -15V, V_{GS} = -10V,$ $I_D = -6A$	N-CH		11.5		nC
	$Q_g(V_{GS}=4.5V)$ $Q_g(V_{GS}=-4.5V)$		P-CH		9		
			N-CH		5		
			P-CH		5.8		
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$		N-CH		1.6		
			P-CH		2.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$		N-CH		2.8		
			P-CH		2.5		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	N-CH $V_{DS} = 15V,$ $I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$ P-CH $V_{DS} = -15V,$ $I_D = -1A, V_{GS} = -10V, R_{GS} = 6\Omega$	N-CH		11		nS
Rise Time <sup>1,2</sup>	$t_r$		P-CH		10		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$		N-CH		16		
Fall Time <sup>1,2</sup>	$t_f$		P-CH		15		
			N-CH		36		
			P-CH		28		
			N-CH		20		
			P-CH		15		

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_c = 25^\circ C$ )**

Continuous Current	$I_S$	$I_F = I_S, V_{GS} = 0V$	N-CH		2.3	A
			P-CH		-2.3	
Pulsed Current <sup>3</sup>	$I_{SM}$	$I_F = I_S, dI_F/dt = 100A / \mu s$	N-CH		9.2	nS
			P-CH		-9.2	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$	N-CH		1.2	V
			P-CH		-1.2	
Reverse Recovery Time	$t_{rr}$	$I_F = I_S, dI_F/dt = 100A / \mu s$	N-CH		50	nS
Peak Reverse Recovery Current	$I_{RM(REC)}$		P-CH		55	
			N-CH		30	A
Reverse Recovery Charge	$Q_{rr}$		P-CH		-22	
			N-CH		2	nC
			P-CH		2.1	

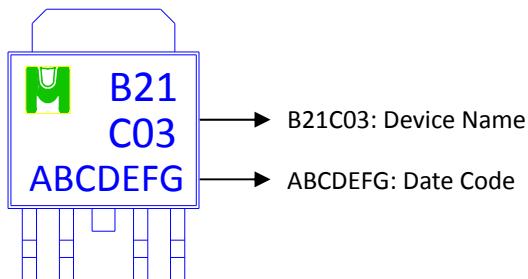
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

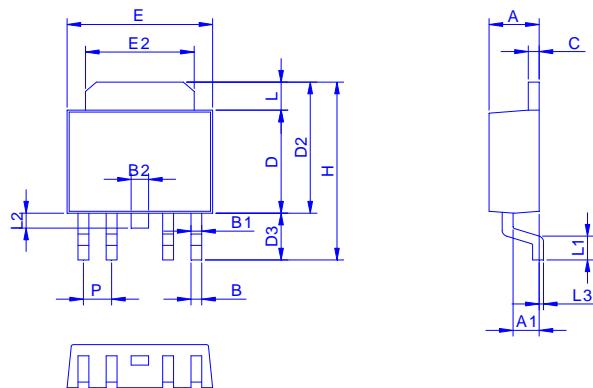
<sup>3</sup>Pulse width limited by maximum junction temperature.

### Ordering & Marking Information:

Device Name: EMB21C03A for DPAK (TO-252)

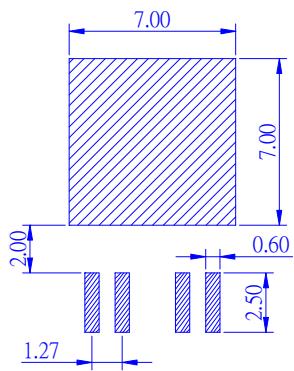


### Outline Drawing

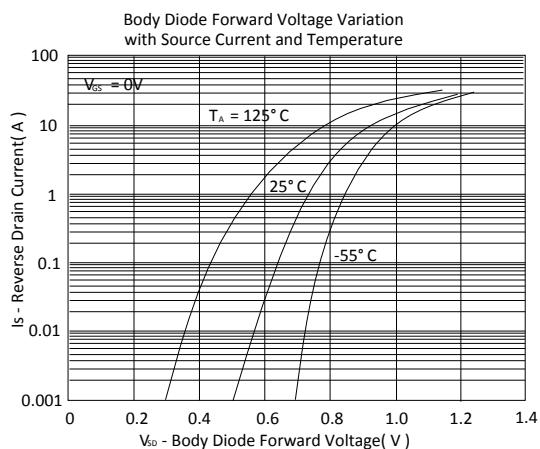
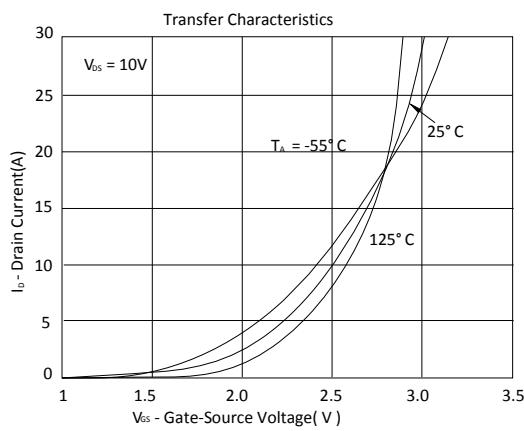
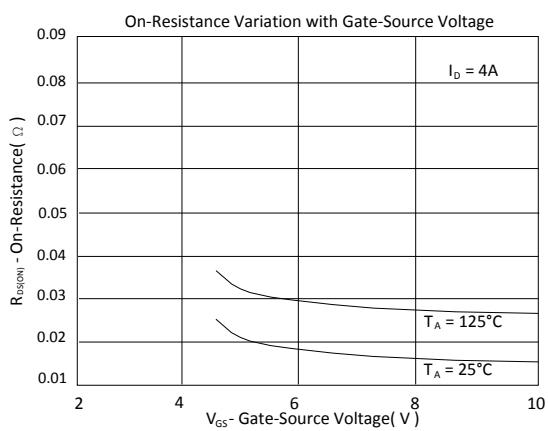
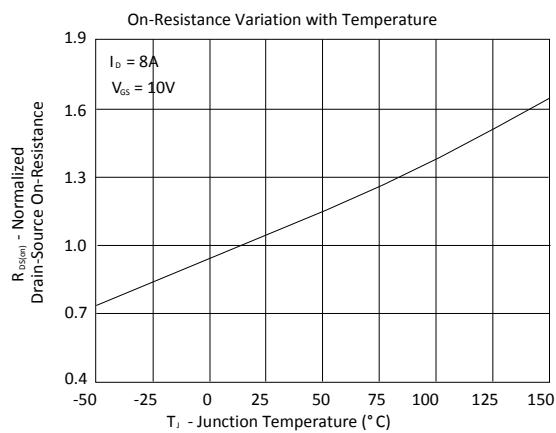
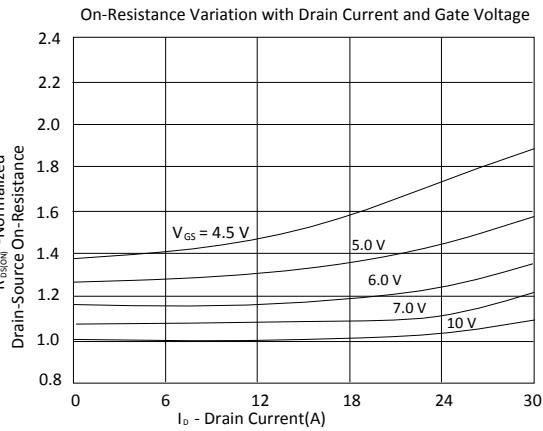
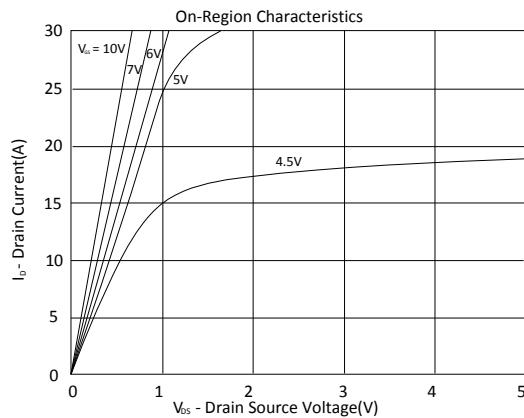


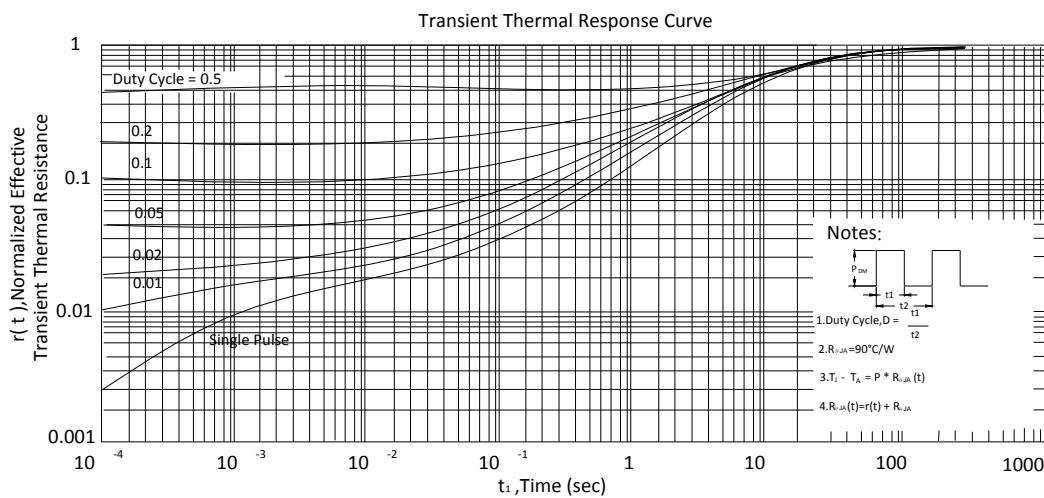
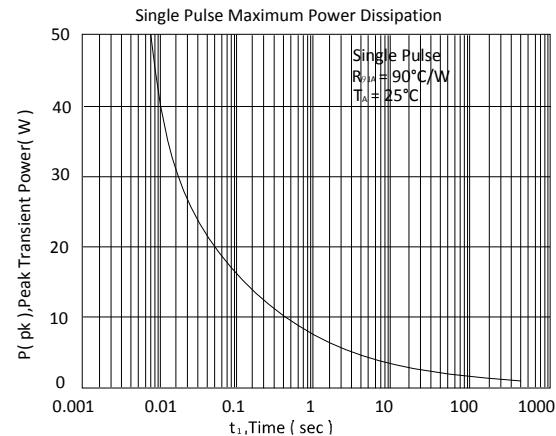
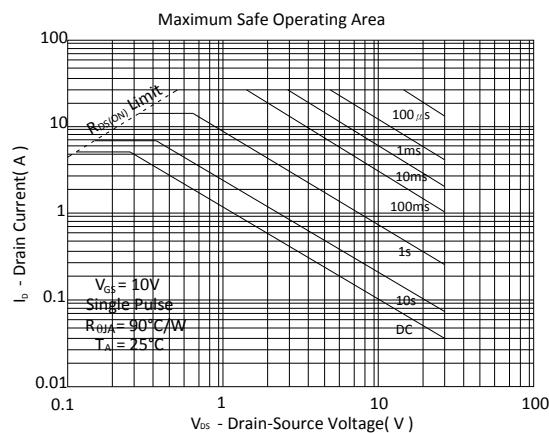
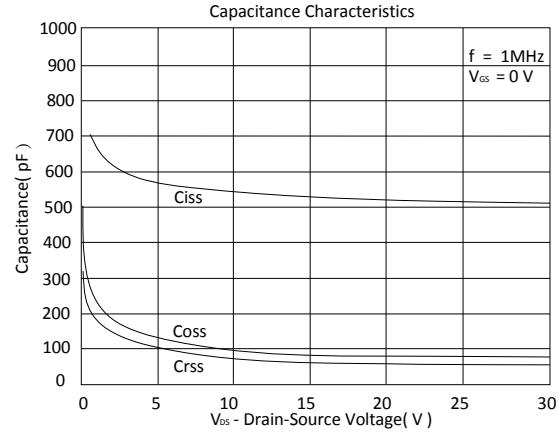
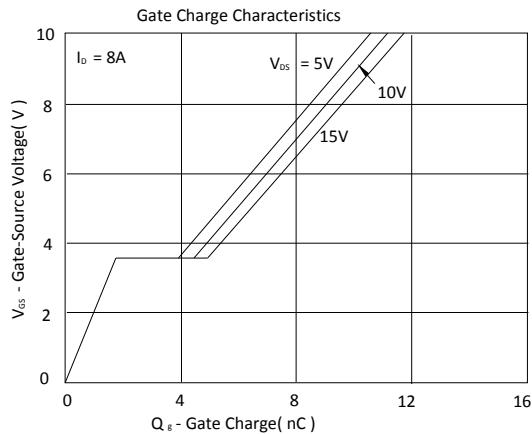
Dimension in mm

Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	1.10	0.30	0.55	0.40	0.40	5.30	6.70	2.20	6.30	4.80	9.20	1.30	0.90	0.50	0.00	1.17
Max.	2.50	1.30	0.70	0.75	0.80	0.60	5.70	7.30	3.00	6.70	5.45	10.15	1.70	1.50	1.10	0.30	1.37



### N-Channel







P-Channel

